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PUBLICATION FONDAMENTALE EN CEM

Specification for radio disturbance and immunity measuring apparatus and methods –

Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements

Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –

Partie 2-1: Méthodes de mesure des perturbations et de l'immunité – Mesures des perturbations conduites



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements

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This third edition cancels and replaces the second edition published in 2008, Amendment 1:2010 and Amendment 2:2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition: Methods of measurement using a new type of ancillary equipment – the CDNE – are added.

The text of this standard is based on the following documents:

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

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SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements

1 Scope

This part of CISPR 16 is designated a basic standard, which specifies the methods of measurement of disturbance phenomena in general in the frequency range 9 kHz to 18 GHz and especially of conducted disturbance phenomena in the frequency range 9 kHz to 30 MHz. With a CDNE, the frequency range is 9 kHz to 300 Hz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 14-1, *Electromagnetic compatibility – Requirements for household appliances, electric tools and similar apparatus – Part 1: Emission*

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-1-2:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements*

CISPR 16-4-2, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Uncertainty in EMC measurements*

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